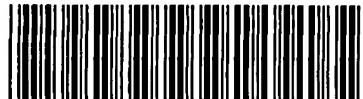


**Search Notes****Application/Control No.**

10/777,026

**Examiner**

Binh X. Tran

**Applicant(s)/Patent under Reexamination**

KAWAGUCHI ET AL.

**Art Unit**

1765

**SEARCHED**

Class	Subclass	Date	Examiner
216	68	10/4/2007	BT
216	69	10/04/2007	BT
216	73	10/4/2007	BT
438	715	10/4/2007	BT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using database in EAST	10/4/2007	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner